PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

**APPLICANTS: Adachi Masaaki; BEST AVAILABLE **FOREIGN APPLICATIONS VERIFIED: JAPAN 2001-267786 09/04/2001	COPY
BEST AVAILABLE CONTINUING DATA VERIFIED:	CO _I ;
FOREIGN APPLICATIONS VERIFIED:	CO _{i~ ;}
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FOREIGN APPLICATIONS VERIFIED:	CO _F
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APAN 2001-267786 09/04/2001	
PG-PUB DO NOT PUBLISH ☐ RESCIND ☐ ATTORN	IEY DOCKET NO
5 USC 119 conditions met □ yes □ no	
erified and Acknowledged Examiners's initials 220102U	
TLE: Profile measuring method and measurement apparatus using interfe	erence of light
	OF COMMIPAT & TM-PTO-436L/Rev. 12-3

NOTICE OF ALLOWANCE MAILED			CLAIMS ALLOWED				
		Assistant Examiner	Total Claims		Print Claim for O.G		
ISSUE FEE			DRAWING				
Amount Due	Date Paid	1	Sheets Drwg.	Figs.Drwg.	Print Fig.		
		Primary Examiner		<u> </u>			
TERMINAL			A II Aire Evernings				
		PREPARED FOR ISSUE	Application Examiner				
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